



BSI Standards Publication

## Semiconductor devices

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Part 5-12: Optoelectronic devices — Light emitting diodes — Test method of LED efficiencies

## National foreword

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# TECHNICAL REPORT



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**Semiconductor devices –  
Part 5-12: Optoelectronic devices – Light emitting diodes – Test method of LED  
efficiencies**

INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

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## CONTENTS

FOREWORD.....	5
INTRODUCTION.....	7
1 Scope.....	8
2 Normative reference .....	8
3 Terms and definitions .....	8
3.1 General terms and definitions .....	9
3.2 Terms and definitions relating to the optoelectronic efficiencies .....	9
3.3 Terms and definitions relating to measuring the efficiencies.....	11
3.4 Terms and definitions relating to measuring current components .....	12
3.5 Abbreviated terms.....	12
4 LED efficiencies.....	13
4.1 General.....	13
4.2 Theoretical background of optoelectronic efficiencies .....	15
4.3 Separate measurement of various efficiencies .....	20
4.4 Requirements for accurate and reliable IQE measurement.....	20
4.5 Classification of IQE measurement methods .....	21
5 Conventional IQE measurement methods: features and limitations .....	22
5.1 Calculation of the LEE .....	22
5.2 Temperature-dependent photoluminescence (TDPL).....	22
5.3 Intensity-dependent photoluminescence (IDPL) or simply photoluminescence (PL) .....	23
5.4 Temperature-dependent time-resolved photoluminescence (TD-TRPL) .....	26
5.5 Time-resolved photoluminescence (TRPL) .....	28
5.6 Time-resolved electroluminescence (TREL) .....	34
5.7 Constant ABC model.....	39
5.8 Constant AB model .....	45
6 Standard IQE measurement method I: TDEL .....	46
6.1 Temperature-dependent electroluminescence (TDEL) method .....	46
6.2 Temperature-dependent radiant power.....	46
6.3 Evaluation of the IQE .....	47
6.4 Validity of the TDEL: examples of blue LEDs .....	49
6.5 Sequence of IQE determination by the TDEL .....	50
6.6 Summary of the TDEL.....	51
7 Standard IQE measurement method II: RTRM .....	51
7.1 Room-temperature reference-point method (RTRM).....	51
7.2 Recombination coefficients, <i>A</i> , <i>B</i> , and <i>C</i> in semiconductors .....	52
7.3 Strategy of the IQE measurement just at an operating temperature.....	53
7.4 Theoretical background of the RTRM .....	54
7.5 Example of the RTRM .....	56
7.6 Comparison of IQEs by the TDEL and the RTRM .....	59
7.7 Summary of the RTRM.....	60
8 The RTRM versus the TDEL and the constant ABC model: comparisons .....	60
9 LED performance issues related to the IQE measurement .....	67
9.1 Various LED efficiency measurement.....	67
9.2 Radiative and nonradiative currents .....	70
9.3 The active efficiency (AE): IQE versus forward voltage .....	74

10 Conclusion: test method of optoelectronic efficiencies of LEDs.....	80
Bibliography.....	81
Figure 1 – Sequence of the efficiency measurements .....	20
Figure 2 – Theoretical model for analysing the TRPL experiment.....	30
Figure 3 – Schematic TRPL response and its interpretation in terms of various lifetimes.....	32
Figure 4 – Temporal responses of the TRPL for three samples .....	33
Figure 5 – Fitted results of the measured TRPL response .....	34
Figure 6 – Schematic diagram of the pulse current injection.....	35
Figure 7 – Square of $1/\tau_{EL}$ as a function of current density for a bias voltage .....	39
Figure 8 – Estimated IQE (left axis) and measured EQE (right axis) versus current density.....	39
Figure 9 – Experimental EQE curve of a blue LED .....	42
Figure 10 – Normalized EQE curves (solid lines) and experimental data (rectangular symbols) for different IQE peak values as a parameter for a blue LED emitting at 460 nm .....	42
Figure 11 – SRH nonradiative carrier lifetime $\tau_{SRH}(=1/A)$ as a function of the $C$ coefficient calculated from Equation (82) .....	43
Figure 12 – Experimental EQE curve of a blue LED .....	43
Figure 13 – Temperature characteristics of an LED.....	47
Figure 14 – IQEs as a function of current at various operating temperatures from room to cryogenic measured by the TDEL method.....	49
Figure 15 – Two different cases of normalized EQE curves as a function of current at various temperatures .....	50
Figure 16 – Sequence of the IQE measurement by the TDEL method .....	51
Figure 17 – Comparison between the conventional ABC model and the improved AB model .....	54
Figure 18 – Calculation procedure from a relative EQE curve to an IQE curve with the RTRM .....	54
Figure 19 – IQE calculation procedure as a function of current based on the RTRM.....	57
Figure 20 – Example of the IQE calculation based on the RTRM.....	59
Figure 21 – Comparison of the IQEs evaluated by (a) the TDEL and (b) the RTRM.....	60
Figure 22 – Radiant power versus current of a blue LED sample measured at various temperatures .....	61
Figure 23 – Normalized intensities on linear and log scales measured at various temperatures .....	62
Figure 24 – $I$ - $V$ characteristics at various temperatures.....	63
Figure 25 – Calculated $a_2$ as a function of current for various temperatures. $I_{ref}$ at 300 K is the current giving the minimum value of $a_2$ in region II. ....	64
Figure 26 – IQEs obtained by the RTRM (symbols) and the TDEL (solid lines) at various temperatures .....	64
Figure 27 – Comparison of the IE obtained from $a_2$ at 300 K (left axis) and the theoretical IE for constant $I_{leak}$ (right axis).....	65
Figure 28 – Normalized EQE and the fitting by the constant ABC model .....	66
Figure 29 – Ratio of the SRH, radiative, Auger recombination currents to the total current.....	66

Figure 30 – Radiant power and forward voltage as a function of forward current.....	68
Figure 31 – Calculation of the mean photon energy from the emission spectra .....	69
Figure 32 – LED efficiencies as a function of forward current.....	70
Figure 33 – Sequence of the radiative and nonradiative current measurements .....	72
Figure 34 – IQE and forward voltage as a function of forward current .....	72
Figure 35 – Radiative current and forward voltage as a function of forward current.....	73
Figure 36 – Nonradiative current and forward voltage as a function of forward current.....	73
Figure 37 – Total forward current, radiative current, and nonradiative current plotted as a function of forward voltage.....	74
Figure 38 – Distribution of the IQE and $V_F$ for 31 blue MQW LEDs .....	76
Figure 39 – Optoelectronic characteristics of three samples under consideration .....	77
Figure 40 – Separated radiative and nonradiative current densities of samples 1 and 2 .....	78
Figure 41 – Separated radiative and nonradiative current densities of samples 1 and 3 .....	79
Table 1 – LED items and their measuring methods listed in IEC 60747-5-6:2016 .....	14
Table 2 – Summary of efficiency items defined in IEC 60747-5-8:2019 .....	19
Table 3 – Various LED IQE measurement methods.....	22
Table 4 – Parameters in IQE and current density versus voltage curves .....	77
Table 5 – Comparison of recombination mechanisms between samples.....	79

## INTERNATIONAL ELECTROTECHNICAL COMMISSION

## SEMICONDUCTOR DEVICES –

**Part 5-12: Optoelectronic devices – Light emitting diodes –  
Test method of LED efficiencies**

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IEC TR 60747-5-12 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices. It is a Technical Report.

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Draft	Report on voting
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Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this Technical Report is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at [www.iec.ch/members\\_experts/refdocs](http://www.iec.ch/members_experts/refdocs). The main document types developed by IEC are described in greater detail at [www.iec.ch/standardsdev/publications](http://www.iec.ch/standardsdev/publications).

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## INTRODUCTION

The latest international standards for light emitting diode (LED) devices are IEC 60747-5-6:2016, IEC 60747-5-8:2019, IEC 60747-5-9:2019, IEC 60747-5-10:2019, and IEC 60747-5-11:2019, where terminology and measuring methods of basic electrical and optical characteristics of LEDs are given.

This technical report gives guidance on the terminology and the measuring methods of various efficiencies of single light emitting diode (LED) chip or package without phosphor. White LEDs for lighting applications are out of the scope of this part of IEC 60747-5-12.

The efficiencies whose measuring methods are described in this technical report are the power efficiency (PE), the external quantum efficiency (EQE), the voltage efficiency (VE), the internal quantum efficiency (IQE), and the light extraction efficiency (LEE). To measure these efficiencies separately, one needs the measurement data of the internal quantum efficiency (IQE).

The IQE is a key performance parameter that represents the quality of epitaxial wafers and contains essential information on operational mechanisms. Requirements for accurate and reliable IQE measurements are suggested. The various IQE measurement methods reported so far are reviewed in detail from a theoretical and practical point of view. Subsequently, the technical limitations for these IQE measurement methods to meet the requirements for accurate and reliable IQE measurements are discussed.

In particular, two different measuring methods of the IQE that can meet the requirements are described in detail both experimentally and theoretically. They are known as the temperature-dependent electroluminescence (TDEL) and the room-temperature reference-point method (RTRM).

A measuring procedure of PE, EQE, VE, IQE, and LEE are demonstrated. But the injection efficiency (IE) and the radiative efficiency (RE) are described for definitions only.

Separate knowledge of various efficiencies of the LED chip or package is able to improve optoelectronic performances of LED chip itself and to design LED application systems such as LED lamps more efficiently and reliably.

## SEMICONDUCTOR DEVICES –

### Part 5-12: Optoelectronic devices – Light emitting diodes – Test method of LED efficiencies

#### 1 Scope

This technical report discusses the terminology and the measuring methods of optoelectronic efficiencies of single light emitting diode (LED) chip or package without phosphor. White LEDs for lighting applications are out of the scope of this part.

This technical report provides guidance on

- terminology of optoelectronic efficiencies of single LED chip or package without phosphor, such as the power efficiency (PE), the external quantum efficiency (EQE), the voltage efficiency (VE), the light extraction efficiency (LEE), the internal quantum efficiency (IQE), the injection efficiency (IE), and the radiative efficiency (RE) [1]<sup>1</sup>;
- test methods of optoelectronic efficiencies of the PE, the EQE, the VE, the LEE, and the IQE [1];
- review of various IQE measurement methods reported so far in view of accuracy and practical applicability;
- the measuring method of the LED IQE based on the temperature-dependent electroluminescence (TDEL) [2];
- the measuring method of the LED IQE based on the room-temperature reference-point method (RTRM) [3];
- the measuring method of the radiative and nonradiative currents of an LED [4];
- the relationship between the IQE and the VE, which leads to introduction of a new LED efficiency, the active efficiency (AE) as  $AE = VE \times IQE$ .

#### 2 Normative reference

The following document is referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60747-5-6, *Semiconductor devices – Part 5-6: Optoelectronic devices – Light emitting diodes*

#### 3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

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<sup>1</sup> Numbers in square brackets refer to the Bibliography.